Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/645,962	FARRAR ET AL.	
Examiner	Art Unit	
Hieu Phan	3738	

SEARCHED				
Class	Subclass	Date	Examiner	
623	17.19 17.18 17.17	12/10/2005	2	
623	23.75			
1	23.76			
	23.48 23.58			
	23.72		1	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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